

32, 64, 96, 128, 192, 256, 384, 512, 640MB, and 1, 1.2, 1.8, 2, 3, 4GB 2.5-Inch IDE Flash Drives

FEATURES

- Capacities from 32MB to 4GB
- Standard IDE Drive Form Factor of 2.5-Inch
- Standard IDE connector and Interface
- Configures to Master or Slave IDE device
- Replaces IDE hard drive for applications where tough environments prohibit use of traditional rotating media
- Solid-State (no moving parts)
- High Shock and Vibration Limits
- 512 Byte Sector and ECC Defect Management Compatible to IDE Hard Disk Drives
- No “Spin” Noise Compared to Traditional Rotating Media
- Available in Commercial, Extended, and Industrial Operating Temperature Ranges

ORDERING INFORMATION

SimpleTech P/N*	Capacity
• STI-FLD25/32(E/I)	32 MBytes
• STI-FLD25/64(E/I)	64 MBytes
• STI-FLD25/96(E/I)	96 MBytes
• STI-FLD25/128(E/I)	128 MBytes
• STI-FLD25/192(E/I)	192 MBytes
• STI-FLD25/256(E/I)	256 MBytes
• STI-FLD25/384(E/I)	384 MBytes
• STI-FLD25/512(E/I)	512 MBytes
• STI-FLD25/640(E/I)	640 MBytes
• STI-FLD25/1GB(E/I)	1 GBytes
• STI-FLD25/1.2GB(E/I)	1.2 GBytes
• STI-FLD25/1.8GB(E/I)	1.8 GBytes
• STI-FLD25/2GB(E/I)	2 GBytes
• STI-FLD25/3GB(E/I)	3 GBytes
• STI-FLD25/4GB(E/I)	4 GBytes

* Custom capacities available

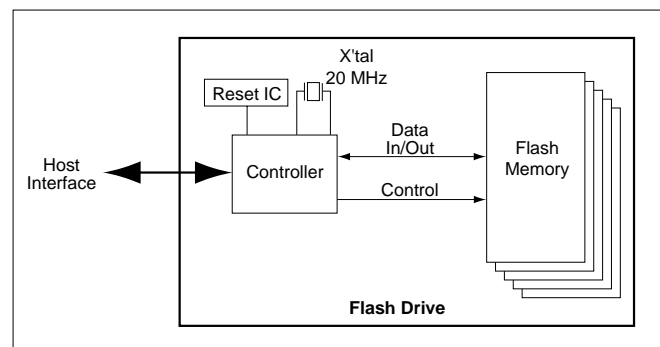
An “E” suffix added to the part number selects the Extended Operating Temperature range option. An “I” suffix added to the part number selects the Industrial Operating Temperature range option. A part number without the “E” or “I” suffix selects the Commercial Operating Temperature option.

GENERAL DESCRIPTION

The SimpleTech STI-FLD25/32(E/I) to STI-FLD25/4GB(E/I) are solid-state flash IDE drives with capacities of 32MB to 4GB and with a standard 2.5-inch form factor.

The IDE drive consists of an IDE controller and an array of flash memory devices. The IDE drive supports the standard ATA register and command set.

FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION

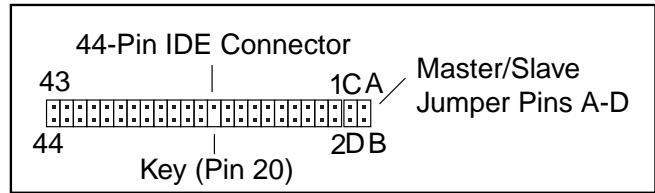
44-Pin IDE Connector

Pin Symbols

Pin Num	Pin Symbol	Pin Num	Pin Symbol
1	-RESET	23	-IOWR
2	GND	24	GND
3	D07	25	-IORD
4	D08	26	GND
5	D06	27	IORDY
6	D09	28	-CSEL
7	D05	29	-DACK
8	D10	30	GND
9	D04	31	HINT
10	D11	32	-IOIS16
11	D03	33	A1
12	D12	34	-PDIAG
13	D02	35	A0
14	D13	36	A2
15	D01	37	-CE1
16	D14	38	-CE2
17	D00	39	-DASP
18	D15	40	GND
19	GND	41	VCC
20	Key	42	VCC
21	DREQ	43	GND
22	GND	44	NC

"-" indicates signal is active low.

Pin Locations



Jumper Settings

<p>43 5 3 1 C A</p>	<p>If all pins A, B, C, and D are open, the drive is in master mode.</p>
<p>44 6 4 2 D B</p>	
<p>43 5 3 1 C A</p>	<p>If pin A is jumpered to pin B, the drive is in slave mode.</p>
<p>44 6 4 2 D B</p>	
<p>43 5 3 1 C A</p>	<p>If pin B is jumpered to pin D, the drive mode is determined by the -CSEL signal (Pin 28).</p>
<p>44 6 4 2 D B</p>	

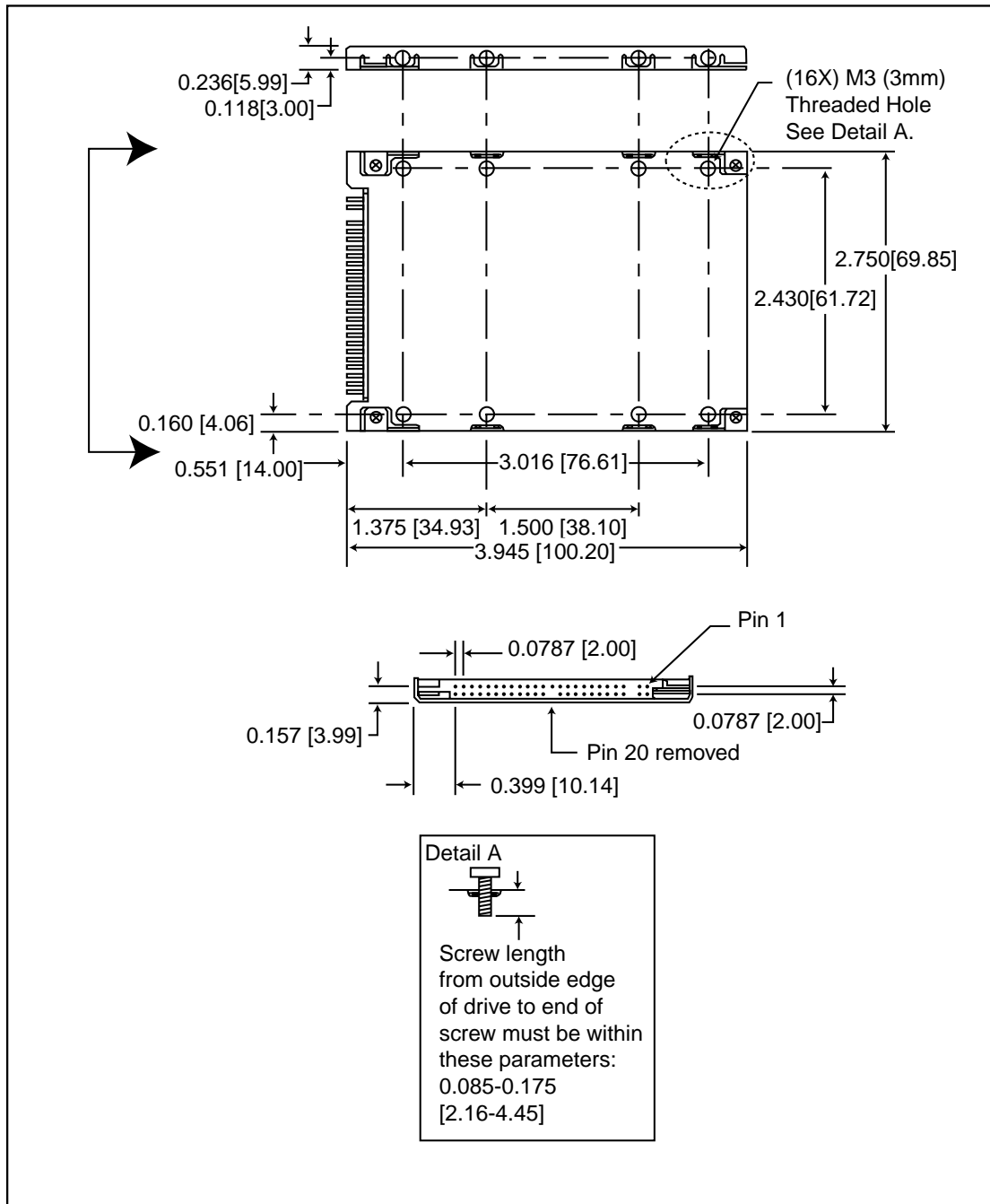
NOTE: In multiple drive configuration, it may become necessary to establish master drive and slave drive. This can be done by booting the PC and using IDE HDD Auto Detection available in CMOS setup.

Signal Description

Signal Name	Dir	Pin	Description
-DASP	I/O	39 TTL I/O 3mA Output 100K Pullup	This input/output is the Disk Active/Slave Present signal in the Master/Slave handshake protocol.
D15-D00	I/O	18, 16, 14, 12, 10, 8, 6, 4, 3, 5, 7, 9, 11, 13, 15, 17 TTL I/O 3mA Output	All Task File operations occur in byte mode on the low order bus D00-D07 while all data transfers are 16 bit using D00-D15.
-IOWR	I	23 TTL Schmitt Trigger Input 100K Pullup	The I/O Write strobe pulse is used to clock I/O data on the Card Data bus into the Drive controller registers when the Drive is configured to use the I/O interface. The clocking will occur on the negative to positive edge of the signal (trailing edge).
-IORD	I	25 TTL Schmitt Trigger Input 100K Pullup	This is an I/O Read strobe generated by the host. This signal gates I/O data onto the bus from the Drive.
HINT	O	31 TTL Tri-State 3mA Output	Signal is the active high Interrupt Request to the host.
A2-A0	I	35, 33, 36 TTL Input	A[2:0] are used to select the one of eight registers in the Task File.
-CE1, -CE2	I	37, 38 TTL Schmitt Trigger Input 100K Pullup	-CE1 is the chip select for the task file registers while -CE2 is used to select the Alternate Status Register and the Device Control Register.
-CSEL	I	28 TTL Input 100K Pullup	This internally pulled up signal is used to configure this device as a Master or a Slave. When the pin is grounded, this device is configured as a Master. When the pin is open, this device is configured as a Slave
-IO16	O	32 TTL Tri-State 3mA Output	This output signal is asserted low when this device is expecting a word data transfer cycle.
-PDIAG	I/O	34 TTL I/O 3mA Output 100K Pullup	This input/output is the Pass Diagnostic signal in the Master/Slave handshake protocol.
-DREQ	O	21	DMA transfer request.
-DACK	I	29	DMA request acknowledge.
-IORDY	O	27 TTL Output 3mA Output	This output signal may be used as IORDY.
-RESET	I	1 TTL Input 100K Pullup	This input pin is the active low hardware reset from the host.
VCC	—	40, 43	Power.
GND	—	2, 19, 22, 26 30, 40	Ground.
Key	—	20	This pin is keyed to ensure cable is connected with the proper orientation.

PACKAGE DIMENSIONS

Refer to the figure below for package dimensions of the 2.5-inch FlashDrive. The units are inches (in parenthesis, millimeters), and the tolerances are ± 0.005 inches (0.127mm) unless otherwise specified.



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit	Note
All input/output voltages	Vin, Vout	-0.3 to VCC+0.3	V	1
VCC voltage	VCC	-0.3 to +6.7	V	
Storage Temperature range	Tstg	-55 to +125	°C	

1. Vin, Vout min=-2.0V for pulse width <=20 ns

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Min	Typ	Max	Unit
Commercial operating temperature	Ta	0	25	70	°C
Extended operating temperature	Ta	-25	—	85	°C
Industrial operating temperature	Ta	-40	—	85	°C
VCC voltage	VCC	4.75	5.0	5.25	V

PERFORMANCE

Item	Performance
Start Up Times (Reset to Ready)	100 ms
Start Up Times (Sleep to Idle)	2 ms
Data Transfer Rate To/From Host	8 MBytes/s (burst)
Controller Overhead (Command to DRQ)	2 ms
Data Transfer Cycle End to Ready (Sector Write)	2 ms
Read	1.5 MBytes/s
Write	3 MBytes

RELIABILITY

Item	Value
Data Write/Erase Endurance	100,000 cycles
Data reliability	1 in 10 ¹⁴ bits, read

CAPACITANCE (Ta=25°C, f=1MHz)

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions
Input Capacitance	Cin	—	—	15	pF	(Vin=0V)
Output Capacitance	Cout	—	—	15	pF	(Vout=0V)

ENVIRONMENTAL CHARACTERISTICS

Item	Value*
Shock	500G, 3 cycles/Axis X, Y, Z/Unit
Vibration (Logarithmic Digital Sine)	freq=100-2000Hz, 20G, 3 sweeps/Axis X, Y, Z/Unit